X-ray Microscopy and Spectroscopy

at Synchrotron Light Sources

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Lawrence Berkeley AB National Laboratory

Last Months Tutorial: Electron Microscopy

Light microscope

- Uses visible light
- Minimum sample prep
- Inexpensive equipment
- Live or dead samples
- No screen/camera needed
- Resolution ~ 10⁻⁷m



(a) Radiolarian under light microscope



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(b) Radiolarian under electron microscope
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Electron microscope

- Uses electrons
- Thin, clean sample
- Expensive, high maintenance
- Dead samples
- Screen/camera is required
- Resolution < 10⁻¹⁰ m



spectromicroscopy

X-rays

- Minimum sample prep
- Do not interact strongly with light elements
- Large field of view
- Average structure atomic structure
- Real-space resolution ~ 10⁻⁹ m

Electrons

High resolution TEM Pt crystal

- Sample must be thin, clean
- Interact strongly with light elements
- Small field of view
- Probe local structural changes
- Resolution < 10⁻¹⁰ m



Electron Microscopy: Introduction, Applications and Opportunities

lectron microscopy is a high-resolution suite of characterization techniques seed in the physical and biological sciences. By accelerating electrons to elabivitic speeds (i.e. 0.54; such that their characteristic wavelengths are 00.000 times smaller than visible light, one can perform high-resolution anging down to the atomic scale. Furthermore, by implementing an array d diffraction and spectroscopic methods, electron microscopy can be used o desphere the nanoscale structure and composition of materials. This utorial will begin by introducing electron microscopy and highlighting its duratages and disadvantages over visible and x-ray characterization chinques. Following this, the applications of electron microscopy will be ummarized, with a specific focur on the outring-edge experiments being enformed by members of the STROBE community.







SEM image of a diaton

Synchrotron Facilities

- Circular particle accelerators
- Produce particularly bright x-rays
 - Billion times brighter than the sun
 - Trillion times brighter than medical x-rays
- Interaction of x-rays with materials is used to perform state-of-the-art research in:
 - Biology
 - Chemistry
 - Physics
 - Materials Sciences
 - Energy Sciences
 - Environmental Sciences



Chemical Earth and Environmental Life Materials Physical Applied



The Synchrotron

When a moving electron changes direction, it emits energy. When the electron is moving fast enough, the emitted energy is at x-ray wavelength.

- LINAC: electrons are produced in an electron gun, packed in bunches and accelerated to an energy of 50MeV
- Booster Ring: pre-accelerator that increases the speed of the electrons to 1.9 GeV
- Storage Ring: hair thin electron beam is stored in a 200 m ring where they travel at 99.99996 % the speed of light – 299,792,447 m/s
- **Beamlines**: the x-ray beams emitted by the electrons are directed toward the "beamlines". Each beamline is designed for use with a specific technique or for a specific type of research.





https://als.lbl.gov/

Storage Ring

Linear segments and curved with special magnets

• Bending magnets force the electrons into their orbital path

 $\frac{\Delta\omega}{\omega} \approx \frac{1}{N}$

 $\theta_{\rm cen} \simeq \frac{1}{\gamma \sqrt{N}}$

= N

Photon energy

Insertion devices create high energy x-rays





ALS Beamlines



https://als.lbl.gov/



Bending Magnets: Force electrons into orbital path and emit a spray of x-rays tangentially to the plane of the electron beam



Storage Ring

Undulator (Insertion Device): a complex array of small bending magnets with alternating polarity, force the electrons to follow an undulating, or wavy, trajectory. The radiation emitted at each consecutive bend overlaps and interferes



Synchrotron Radiation

Soft x-rays:

wavelengths bigger than 0.10 nm or energies smaller than10 keV

- \rightarrow Higher absorption
- \rightarrow Higher chemical sensitivity
- \rightarrow Bonding states

Hard x-rays:

wavelengths of 0.10 to 0.01 nm or energies in the range 10 to 120 keV

- \rightarrow Higher Penetration
- →Crystal lattice / strain information
- →Fluorescence





40 Beamlines at the ALS

ALS Beamlines

Quantum Materials (MAESTRO) 7.0.2 Coherent Scattering and Microscopy (COSMIC) 7.0.1 Calibration, Optics Testing, Spectroscopy 6.3.2 Magnetic Spectroscopy / Materials Science 6.3.1 Full-Field Transmission Soft X-Ray Microscopy 6.1.2 Energy, Catalytic, and Chemical Science (AMBER) 6.0.1 Double-Dispersion RIXS (QERLIN) 6.0.2 Polymer STXM 5.3.2.2 STXM 5.3.2.1 Research and Development 5.3.1 Macromolecular Crystallography (BCSB) 5.0.3 Macromolecular Crystallography (BCSB) 5.0.2 Macromolecular Crystallography (BCSB) 5.0.1 Macromolecular Crystallography (MBC) 4.2.2 High-Resolution Spectroscopy (MERLIN) 4.0.3 Magnetic Spectroscopy and Scattering 4.0.2 General X-Ray Testing Station 3.3.2 X-Ray Footprinting 3.2.1 National Center for X-Ray Tomography 2.1 Macromolecular Crystallography (GEMINI) 2.0.1 IR Imaging and Tomography 2.4 IR Spectromicroscopy 1.4



- 7.3.1 High-Pressure In Situ Soft X-Ray Spectroscopy
- 7.3.3 SAXS/WAXS/GISAXS
- 8.0.1 Surface and Materials Science (RIXS)
- 8.2.1 Macromolecular Crystallography (BCSB/HHMI)
- 8.2.2 Macromolecular Crystallography (BCSB/HHMI)
- 8.3.1 Macromolecular Crystallography (TomAlberTron)
- 8.3.2 Tomography (micro-CT)
- 9.0 Chemical Transformations
- 9.3.1 Tender X-Ray Spectroscopy
- 9.3.2 Ambient-Pressure Soft X-Ray Spectroscopy
- 10.0.1 ARPES, SpinARPES
- 10.3.1 X-Ray Fluorescence Microprobe (XFM)
- 10.3.2 X-Ray Fluorescence Microprobe (XFM)
- 11.0.1 PEEM3/Resonant Soft X-Ray Scattering
- 11.0.2 Molecular Environmental Science
- 11.3.2 EUV Lithography Photomask Imaging (SHARP)
- 12.0.1 EUV Lithography Nanopatterning (MET/MET5)
- 12.0.2 Coherent X-Ray Scattering
- 12.2.1 Small-Molecule Crystallography
- 12.2.2 Diffraction Under Non-Ambient Conditions
- 12.3.1 SIBYLS-MX and SAXS
- 12.3.2 Microdiffraction

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A Typical Beamline

X-ray optics: Modify the raw x-ray beam provided by the accelerator. Specialized mirrors and crystal optics may be used to focus the beam and to select the wavelength, energy, or coherence desired



A Typical Beamline

X-ray optics: Modify the raw x-ray beam provided by the accelerator. Specialized mirrors and crystal optics may be used to focus the beam and to select the wavelength, energy, or coherence desired

Experimental cabin: Beamline specific sample placement in open air, in vacuum or temperature controlled. Can be motorized. Equipped with detectors, such as diodes, scintillators or CCDs suitable for the corresponding technique





The Advanced Light Source -Techniques

Microscopy/Imaging

These techniques use the light-source beam to obtain pictures with fine spatial resolution of the samples under study and are used in diverse research areas such as cell biology, lithography, infrared microscopy, radiology, and x-ray tomography

Spectroscopy

These techniques are used to study the energies of particles that are emitted or absorbed by samples that are exposed to the light-source beam and are commonly used to determine the characteristics of chemical bonding and electron motion

Scattering/Diffraction

These techniques make use of the patterns of light produced when x -ays are deflected by the closely spaced lattice of atoms in solids and are commonly used to determine the structures of crystals and large molecules such as proteins

X-Ray Microscopy

- "Nondestructive" imaging technique image contrast determined by the difference in absorption of x-rays in different components of the sample
- First invented in the 1940s equipped with a photographic film



A.P. Hitchcock / Journal of Electron Spectroscopy and Related Phenomena 200 (2015) 49-63

X-Ray Microscopy

- Tunable soft x-rays: 50 3000 eV → spectrally sensitive imaging, based on systematic changes of the incident photon energy and/or polarization properties of the x-rays
- Synchrotron source or laser-produced plasma
- Higher penetration than electrons
- Resolution between light and electron microscopes ~ 30 nm
- In principle limited by the wavelength

$$A = \frac{hc}{E} = \frac{1.24 \text{ keV nm}}{\text{photon energy (keV)}}$$

- **STXM**: focused beam is rastered over sample
- **TXM**: full field imaging -> faster, reduced brightness

X-rays are focused with **Fresnel Zone Plates**: circular diffraction grating that works as a lens for monochromatic light



I. Snigireva, A. Snigireva, MICROSCOPY TECHNIQUES | X-Ray Microscopy in Encyclopedia of Analytical Science (Second Edition), 2005

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- **XPEEM**: full-field imaging in reflection geometry
- record electrons emitted from a sample in response to the x-ray absorption
- \rightarrow Study chemistry, structure and magnetism of thin films and surfaces



Spectromicroscopy

Inelastic scattering:

Many mechanisms/interactions with loosely bound electrons \rightarrow Loss of energy

Coherent/elastic scattering:

Thomson and Rayleigh scattering/ interactions

with strongly bound electrons

 \rightarrow wavelength stays the same/ no loss in energy

 \rightarrow Can change direction/phase

 \rightarrow Phase shift



Absorption:

- Energy is transferred to an inner atomic electron
- → Elements have different sets of core level energies
- → X-ray absorption near edge structure (XANES)
- → near edge X-ray absorption fine structure (NEXAFS)

\rightarrow Amplitude

J. A Seibert and J. M. Boone, Journal of Nuclear Medicine Technology March 2005, 33 (1) 3-18

Spectromicroscopy



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Energy range of soft X-rays in STXM:

- 1s absorption edges of light elements such as C, N, O, Na, Mg, Al, Si, and P
- 2p absorption edges of elements of environmental relevance such as Fe, Mn, Cr, As, Zn, Ni, Ti, and Ca

Spectromicroscopy



(1) Applying principle component analysis (PCA):

PCA calculates **eigenspectra** and **eigenimages** from the image stack. The eigenspectra are an orthogonal set of spectra that, in linear combination, can describe any observed spectrum in the dataset. The eigenvalue associated with each eigenspectrum gives a typical weighting of that eigenspectrum in the entire data set, so that the later eigenspectra (with small eigenvalues) represent less and less common variations in the data.

(2) Applying cluster analysis:

The cluster analysis is used to classify data in the image stack according to spectral similarities. When searching for clusters, you are looking for pixels with similar weightings of eigenspectra.

ALS Beamlines

COSMIC 7.0.1

Soft X-ray Spectroscopy: Build in 2017 Energy range: 250-2500 eV: High sensitivity for chemical and magnetic states Higher spatial resolution

Scanning Transmission X-ray Microscopy (STXM): Scans the sample with focused X-ray beam and intensity is detected with a diode Resolution is limited by X-ray optics: ~ 50nm

Ptychography: Overlapping scattered signals are detected on CCD High spatial resolution based on instrument precision and scattering of the sample: ~ 8 nm





Versatile Ultrahigh-Resolution Soft X-ray Microscope

Tunable:

- Energy range \rightarrow chemical information
 - Tilt angles \rightarrow 3D information
- X-ray polarization \rightarrow orientational information

Combinable:

- Commercial TEM holders and cells (e.g. Hummingbird Scientific)
- Custom made environmental cells (Prof. Will Chueh of Stanford)

Adjustable (Time Resolved):

- Liquid-flow
- Heating
- Gas-flow
- Electrochemistry
 - Cryogenics

Samples:

- Chemically heterogenous samples
- Morphologically heterogenous samples
 - Geological samples
- Catalysts, Magnetic & Battery materials
 - Biominerals
 - Biological samples (Cryo)









Mi Yoo et al. Energy Environ. Sci. 2020

Linear Dichroic Ptychography – 7.0.1

- Provides orientational information of optically anisotropic materials
- Contrast changes as a function of incident beam polarization and energy
 - → Orientation information of certain chemical bonds



Yuan Hung Lo, et al. PNAS 118(3), e2019068118 (2021)

→ Implementation of automated EPU control, data acquisition and analysis & 3D
→ Determination of precision, resolution and thickness limitation

P1

30°



- X-ray Microscopy An Overview, Encyclopedia of Interfacial Chemistry, 2018
- David A. Shapiro, et al., An ultrahigh-resolution soft x-ray microscope for quantitative analysis of chemically heterogeneous nanomaterials, Science Advances 2020; 6 : eabc4904
- I. Snigireva, A. Snigireva, MICROSCOPY TECHNIQUES | X-Ray Microscopy, Encyclopedia of Analytical Science (Second Edition) 2005
- A.P. Hitchcock / Journal of Electron Spectroscopy and Related Phenomena 200 (2015) 49–63

Ni metalattice

b



Han, Crespi, *Phys. Rev. Lett.* 2002 Liu, Y. *et al. Nano Letters* **18**, 546–552 (2018).



X-ray ptychography of a Ni metalattice

STROBE Research Tutorial Series

Introduction to Coherent Diffractive Imaging: To Ptychography and Beyond

Hybrid seminar Sep-21 Tuesday | 11pm PT | 12pm MT | 2pm ET Everyone is welcome to attend!

UCLA Berkeley FIU

STROBE_STC https://strobe.colorado.edu/

Coherent diffractive imaging (CDI) comprises a set of imaging techniques that replace image-forming optics by any of a wide array of computer algorithms that retrieve an image from the scatter pattern generated by a coherent illumination beam. CDI is particularly attractive for imaging with short-wavelength light, since it enables diffraction-limited imaging with quantitative phase- and amplitude-contrast. This talk will begin with a brief overview of applications of coherent diffractive imaging, and will then focus on ptychography and a few extensions tailored to various cutting-edge applications. Finally, it will provide a brief introduction to practical aspects of implementing coherent diffractive imaging.

STROBE



Dr. Michael Tanksalvala KM Group, CU Boulder

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ptychography reconstruction

https://strobe.colorado.edu/members/tutorials/2021/tutorialintroduction-to-coherent-diffractive-imaging-to-ptychographyand-beyond/

UCI:



~0.2 um

CCD

2



Pt Si Ni + SiO2

X-ray ptychography of a Ni metalattice

This is still only 2D – What if we want to image the internal structure?

Let's try tomography!



















Subtract projection sum



Subtract projection sum



Divide by (N-1) N = # projections



Scalar tomography of Ni metalattice



Scalar tomography of Ni metalattice



Imaging magnetism – XMCD ptychography

XMCD Spectroscopy



Imaging: Combine XMCD with STXM or ptychography



Imaging magnetism in Ni metalattice

2 types of data

Electron density (absolute absorption)

Magnetic field intensity (differential absorption)





Vector ptycho-tomography



Scalar tomography only sees the intensity in a voxel.

XMCD provides the portion of the magnetic field vector that is parallel to the incoming light.

In this configuration, by rotating around the Y axis, we can learn about X and Z axis magnetization, but nothing about Y axis.

By rotating around the X axis we can learn about the Y component of the vector.

Vector ptycho-tomography



Data collection:

At each of 3 in-plane rotations

- \rightarrow At each of 40 tilt angles
 - → Ptychographic imaging with L and R polarized light to calculate XMCD

Note that 3 in-plane rotations are not strictly necessary for vector tomography, but redundant data aids our reconstruction.

Vector ptycho-tomography







4D Spectromicroscopy

ZnO Loaded Al₂O₃ Aerogel Catalyst:



Ptychographic Image Sequence: Varying energies and tilt angles





0.1

0.2

Spatial frequency (nm⁻¹)

Ptychographic Tomography:





Jungjin Park, Young-Sang Yu, Jang-Wook Choi (Seoul National Univ.), in preparation

Chemically Sensitive Ptychographic Tomography:

Quantitative chemical information in 3D Structure Porosity

Hao Yuan*, et al. ACSANM 2021*

0.3

Reconstructed voxel size: $5 \times 5 \times 5 \text{ nm}^3$ 3D resolution : 9 nm

Challenges

Stage stability

- Depending on sample holder, motor may require some settling time
- Sample preparation
- Need at minimum +/- 50 degrees of tilt for tomography
 - Many holders cannot achieve this without running into the OSA, sample must be on 3 mm TEM grid
 - System designed for **transmission** samples: sample must not be too thick or have features that block the light at high tilt angles

Spectroscopic concerns

- Substrate must be transparent to your desired wavelengths
 - This often gives a wider range of options than electron microscopy, however (material and sample holder dependent)
- For magnetic samples, need to ensure magnetization direction is parallel to beam propagation

DATA

- Single tomographic image can take ${\sim}10$ TB of data to produce





Acknowledgements

Vanessa Schoeppler

David Shapiro Young-Sang Yu Matthew Marcus Roger Falcone







Emma Cating-Subramanian Chen-Ting Liao Charles Bevis Robert Karl Sinead Ryan

University of Colorado

Sadegh Yazdi Margaret Murnane Henry Kapteyn

Boulder

- Arjun Rana Yuan Hung Lo Xingyuan Lu Min Pham Yaroslav Tserkovnyak Jianwei Miao Stanley Osher
- UCLA









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